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- Eight D-Type Flip-Flops in a Single Package
- **High-Current 3-State True Outputs Can** Drive up to 15 LSTTL Loads
- Full Parallel Access for Loading
- Package Options Include Plastic Shrink Small-Outline (DB), Small-Outline (DW), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) DIPs

#### description

These 8-bit flip-flops feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The eight flip-flops of the 'HC374 devices are edge-triggered D-type flip-flops. On the positive transition of the clock (CLK) input, the Q outputs are set to the logic levels that were set up at the data (D) inputs.

An output-enable (OE) input places the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load

nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

OE does not affect the internal operations of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to V<sub>CC</sub> through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54HC374 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74HC374 is characterized for operation from -40°C to 85°C.

**FUNCTION TABLE** 

	(each flip-flop)												
	INPUTS		OUTPUT										
OE	CLK	D	Q										
L	$\uparrow$	Н	Н										
L	$\uparrow$	L	L										
L	H or L	Х	Q <sub>0</sub>										
н	Х	Х	Z										



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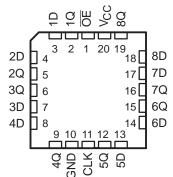


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SN54HC374 J OR W PACKAGE
SN74HC374 DB, DW, N, OR PW PACKAGE
(TOP VIEW)

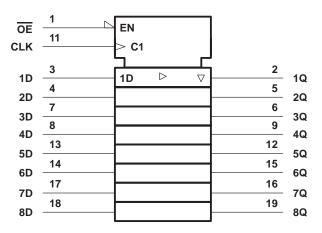
	(	,	
OE 1Q 1D 2D 2Q 3Q 3D 4D 4Q GND	2 3 4 5 6 7	18 17 16 15 14 13	V <sub>CC</sub> 8Q 8D 7D 7Q 6Q 6D 5D 5Q CLK
0.12	۹		

SN54HC374 ... FK PACKAGE (TOP VIEW)



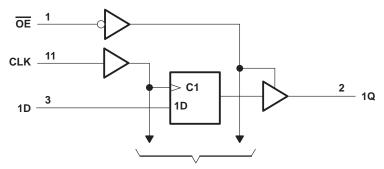
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#### logic symbol<sup>†</sup>



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

### logic diagram (positive logic)



**To Seven Other Channels** 

#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>‡</sup>

	be Note 1) (see Note 1) DB package DW package N package	±20 mA ±20 mA ±35 mA ±70 mA 115°C/W 97°C/W 67°C/W
Storage temperature range, T <sub>stg</sub>	PW package	

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.



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#### recommended operating conditions (see Note 3)

			SI	154HC37	74	SN74HC374		LINUT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		2	5	6	2	5	6	V
		$V_{CC} = 2 V$	1.5			1.5			
$V_{\text{IH}}$	High-level input voltage	$V_{CC} = 4.5 V$	3.15			3.15			V
		ACC = 6 A	4.2			4.2			
	Low-level input voltage	$V_{CC} = 2 V$	0		0.5	0		0.5	
VIL		$V_{CC} = 4.5 V$	0		1.35	0		1.35	V
		ACC = 6 A	0		1.8	0		1.8	
VI	Input voltage		0		VCC	0		VCC	V
VO	Output voltage		0		VCC	0		VCC	V
		$V_{CC} = 2 V$	0		1000	0		1000	
t <sub>t</sub>	Input transition (rise and fall) time	$V_{CC} = 4.5 V$	0		500	0		500	ns
		$V_{CC} = 6 V$	0		400	0		400	
Тд	Operating free-air temperature		-55		125	-40		85	°C

NOTE 3: All unused inputs of the device must be held at VCC or GND to ensure proper device operation. Refer to the TI application report Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CO	NDITIONS	Vee	Т	A = 25°C	;	SN54H	IC374	SN74H	C374	UNIT
PARAMETER	TEST CC	INDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	1.9	1.998		1.9		1.9		
		I <sub>OH</sub> = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
VOH	$V_I = V_{IH} \text{ or } V_{IL}$		6 V	5.9	5.999		5.9		5.9		V
		I <sub>OH</sub> = -6 mA	4.5 V	3.98	4.3		3.7		3.84		
		I <sub>OH</sub> = -7.8 mA	6 V	5.48	5.8		5.2		5.34		
	$V_I = V_{IH} \text{ or } V_{IL}$	I <sub>OL</sub> = 20 μA	2 V		0.002	0.1		0.1		0.1	
			4.5 V		0.001	0.1		0.1		0.1	
V <sub>OL</sub>			6 V		0.001	0.1		0.1		0.1	V
		I <sub>OL</sub> = 6 mA	4.5 V		0.17	0.26		0.4		0.33	
		I <sub>OL</sub> = 7.8 mA	6 V		0.15	0.26		0.4		0.33	
l	$V_I = V_{CC} \text{ or } 0$		6 V		±0.1	±100		±1000		±1000	nA
IOZ	$V_{O} = V_{CC} \text{ or } 0$		6 V		±0.01	±0.5		±10		±5	μΑ
ICC	$V_{I} = V_{CC} \text{ or } 0,$	$I_{O} = 0$	6 V			8		160		80	μΑ
Ci			2 V to 6 V		3	10		10		10	pF



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#### timing requirements over recommended operating free-air temperature range (unless otherwise noted)

		N <sub>e</sub> -		25°C	SN54H	IC374	SN74H	IC374	UNIT
		Vcc	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
		2 V		6		4		5	
fclock	Clock frequency	4.5 V		30		20		24	MHz
		6 V		35		24		28	
		2 V	80		120		100		
tw	Pulse duration, CLK high or low	4.5 V	16		24		20		ns
		6 V	14		20		17		
		2 V	100		150		125		ns
t <sub>su</sub>	Setup time, data before CLK↑	4.5 V	20		30		25		
		6 V	17		25		21		
	Hold time, data after CLK↑	2 V	10		13		12		
th		4.5 V	5		5		5		ns
		6 V	5		5		5		

## switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	Т	<b>₄ = 25°C</b>	;	SN54H	IC374	SN74H	C374	UNIT		
PARAMETER	(INPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT		
			2 V	6	12		4		5				
fmax			4.5 V	30	60		20		24		MHz		
			6 V	35	70		24		28				
			2 V		63	180		270		225			
<sup>t</sup> pd	CLK	Any Q	4.5 V		17	36		54		45	ns		
			6 V		15	31		46		38			
			2 V		60	150		225		190			
t <sub>en</sub>	OE	Any Q	Any Q	Any Q	4.5 V		16	30		45		38	ns
			6 V		14	26		38		32			
			2 V		36	150		225		190			
<sup>t</sup> dis	OE	Any Q	4.5 V		17	30		45		38	ns		
			6 V		16	26		38		32			
			2 V		28	60		90		75			
tt		Any Q	4.5 V		8	12		18		15	ns		
			6 V		6	10		15		13			



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# switching characteristics over recommended operating free-air temperature range, $C_L = 150 \text{ pF}$ (unless otherwise noted) (see Figure 1)

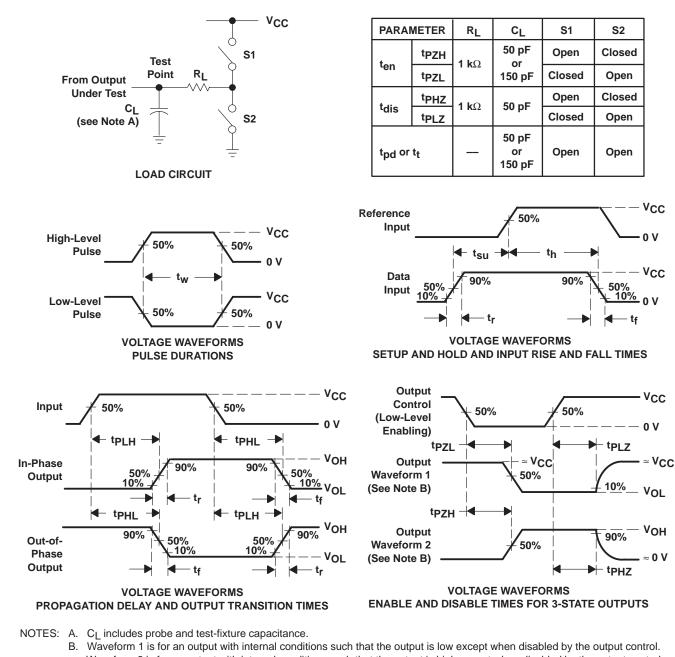
PARAMETER	FROM	то	Vaa	Т	_ = 25°C	;	SN54H	IC374	SN74H	C374	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	6	12				5			
f <sub>max</sub>			4.5 V	30	60				24		MHz	
			6 V	35	70				28			
		Any Q	2 V		80	230		345		290		
<sup>t</sup> pd	CLK		4.5 V		22	46		69		58	ns	
			6 V		19	39		58		49		
			2 V		70	200		300		250		
ten	OE	Any Q	4.5 V		25	40		60		50	ns	
			6 V		22	34		51		43		
		Any Q	2 V		45	210		315		265		
tt			4.5 V		17	42		63		53	ns	
			6 V		13	36		53		45		

## operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
Cpd	Power dissipation capacitance per flip-flop	No load	100	pF

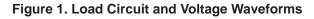


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## PARAMETER MEASUREMENT INFORMATION

- Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, Z<sub>Q</sub> = 50 Ω, t<sub>f</sub> = 6 ns, t<sub>f</sub> = 6 ns.
- D. For clock inputs, fmax is measured when the input duty cycle is 50%.
- E. The outputs are measured one at a time with one input transition per measurement.
- F.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
- G. t<sub>PZL</sub> and t<sub>PZH</sub> are the same as t<sub>en</sub>.
- H. tPLH and tPHL are the same as tpd.





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